

**Search Notes**

Application/Control No.

09/298,453

Examiner

Cong-Lac Huynh

Applicant(s)/Patent under  
Reexamination

BAIN ET AL.

Art Unit

2178

**SEARCHED**

Class	Subclass	Date	Examiner
715	501.1	9/8/2005	CLH
	500	9/8/2005	CLH
	781	9/8/2005	CLH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
715	501.1	9/8/2005	CLH
	500	9/8/2005	CLH
Interference Search History Printout		9/8/2005	CLH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (US-PGPUB, USPAT, EPO, JPO, Derwent)	9/8/2005	CLH
ACM	9/8/2005	CLH
ProQuest	9/8/2005	CLH
IEEE	9/8/2005	CLH